

**Search Notes**

Application/Control No.

10/779,712

Examiner

Wen-Ying P. Chen

Applicant(s)/Patent under  
Reexamination

FUJITA ET AL.

Art Unit

2871

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Citations search of tagged references	12/13/2005	WPC
349/155-157 combined with key word search of all databases in EAST	12/14/2005	WPC
Reviewed previously cited references	12/14/2005	WPC